Sealed quotations are invited for ROUGHNESS PROFILOGRAM for Rock

Technical specifications are:
• Portable Surface Roughness Tester Compact design
• Simple operation
• Operates on various surfaces
• Measurement of Ra or Rz parameters with the touch of a button
• Both Metric & Imperial Modes
• Low battery indication
• Durable carrying case
• Measuring Range: Ra: 0.05 to 10µm & Rz: 0.1 to 50 µm
• Cut-off length: 0.25, 0.8 & 2.5mm
• Tracing Length: 6mm
• Measuring Length: 1.25, 4.0 & 5.0mm
• Operational Temperature: 0 – 40°C

The NIQ should be addressed to Prof. K. S. Rao and to be submitted to Department of Civil Engineering, IIT Delhi, Hauz Khas, New Delhi – 110016, India latest by 5.00 pm on October 15th 2012. Interested parties are required to submit their technical and commercial bids in separately sealed envelopes and marked respectively as “Technical Bid” and “Commercial Bid” on the outside. Price should be quoted to CIF New Delhi (IIT Delhi). The validity of quotation should be at least three months.